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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Gerhard Fritz, et al. Art Unit : Unknown
Serial No. : N/A Examiner : Unknown
Filed : Herewith
Title : ENERGY METERING SYSTEM

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached PTO-1449 form. Under 37 C.F.R. § 1.98 (a)(2)(ii), only copies of foreign patent documents and/or non-patent literature are enclosed. Copies of any listed U.S. patents or U.S. patent application publications can be provided upon request.

This statement is being filed with the application. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date June 27, 2006



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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 14603-025US1	Application No.
Information Disclosure Statement by Applicant (Use several sheets if necessary)		Applicant Gerhard Fritz, et al.	
		Filing Date	Group Art Unit
(37 CFR §1.98(b))			

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	6,417,792	07/09/2002	Eric King et al			
	AB	6,377,037	04/23/2002	Gordon Burns et al			
	AC	6,239,589	05/29/2001	Klaus Windsheimer			
	AD	6,373,415	04/16/2002	Eric King et al			
	AE	5,017,860	05/21/1991	Warren Germer et al			
	AF	4,408,283	10/04/1983	Donald Kovalchik et al			
	AG	US2003/0042886	03/06/2003	Guljeet Gandhi			
	AH	6,555,997	04/29/2003	De Vries , et al.			
	AI	5,545,981	08/13/1996	Dubin et al			

Foreign Patent Documents or Published Foreign Patent Applications							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation
							Yes No
	AJ	2 319 345	05/20/1998	GB			
	AK	0 634 662	01/18/1995	EPO			
	AL	695 21 939	04/04/2002	Germany		Abstract	
	AM	689 20 984	07/06/1995	Germany		Abstract	
	AN	198 42 241	04/06/2000	Germany		Abstract	
	AO	101 62 259	07/17/2003	Germany		Abstract	
	AP						

Other Documents (include Author, Title, Date, and Place of Publication)								
Examiner Initial	Desig. ID	Document						
	AQ	Nagura, H. et al "Correction Method for a Single Chip Power Meter"; IMTC 1994, pp 1313-1316 ISBN 0-7803-1880-3						
	AR							
	AS							
	AT							

Examiner Signature	/Emily Chan/	Date Considered	03/30/2008
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.			

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